

Notice of References Cited

Application/Control No.

10/059,635

Applicant(s)/Patent Under
Reexamination
WEI ET AL.

Examiner

Simon J. Oh

Art Unit

1615

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6372246 B1	04-2002	Wei et al.	424/439
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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